

Leica DM8000 M & DM12000 M

See More, Detect Faster -

High-throughput Inspection Systems



The New Class of Inspection Systems

Inspection, process control and defect analysis of wafers or LCDs and TFTs has to be fast, accurate and ergonomic. Leica Microsystems has many years of experience in developing inspection systems for the semiconductor industry. Using this expertise, we have developed a totally new line of products for the inspection of 8 and 12 inch wafers.

The Leica DM8000 M and Leica DM12000 M optical inspection systems provide an **innovative yet cost-effective system solution** for mastering present and future inspection challenges with confidence.





Larger field for faster inspection

The Leica DM8000 M and the Leica DM12000 M feature an integrated macro mode, giving you four times the field of view of conventional scanning objectives. Seeing more means faster throughput.



Top resolution from every angle

The new Oblique UV (OUV) mode combines oblique illumination with UV light, which enables you to view a sample in top resolution from any angle – and enhances the accuracy of the inspection results.



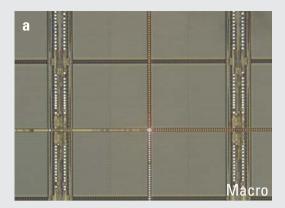
Higher quality due to ergonomic design

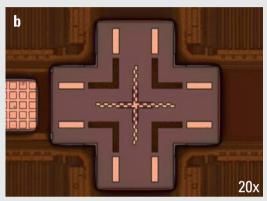
An ergonomic design enables users to work in comfort, enhancing their performance and ultimately improving the quality of their work. The Leica DM8000 M/DM12000 M is specifically designed to provide comfort for long hours at the microscope, and is intuitively operated and easy to adapt to different users' microscopy skill levels.



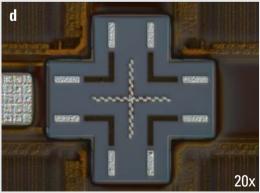
LED illumination for a cleaner environment

The LED illumination integrated in the Leica DM8000 M/DM12000 M optimizes the airflow and creates a cleaner cleanroom. With their long lifetimes and low power consumption, LEDs also have a lower cost of ownership.









Accurate detection in all types of illumination: Quick macro mode scan (a), particle detection in brightfield (b), detection of micro scratches with in-depth darkfield (c), looking for defects on transparent films with the DIC mode (d). It takes less than a second to switch modes, and best of all, the microscope integrates a contrast and illumination manager to support users with little experience using the system.

From Macro to Micro – Defects Don't Stand a Chance



See four times more

To detect macro defects, the Leica DM8000 M and DM12000 M have a micro/macro mode for rapid scanning of large components. The macro magnification captures an object field of approximately $40\ mm$ — that's almost four times more than with conventional scanning objectives. The entire scan area can be accurately scanned for possible defects in a fraction of the time.

Change your perspective by keystroke

If you want to take a closer look, just press a single key to switch from macro to micro mode and inspect the defect in darkfield, brightfield or DIC. Press another key to switch to UV mode for even higher resolution or the OUV mode for a completely new visual experience. **Save valuable time.**



New contrasting techniques for ultra-high resolution

Oblique illumination is an indispensable tool for examining sides, edges or chipping, whereas UV light is useful for obtaining higher resolution. The unique OUV mode combines both techniques. View the sample from all sides, in 3D and in highest resolution.

In-depth darkfield contrast

The in-depth darkfield contrast reveals far more details of samples than conventional optical techniques. What's more, the large working distance protects samples from inadvertent damage during inspection.

For the Demanding Production Environment



Keep the environment clean

LED illumination is integrated with the Leica DM8000 M/DM12000 M. You'll notice the effect of this smart design on your working environment: Without a lamphousing to get in the way, there is an optimal airflow around the microscope. A clean solution for the cleanroom.

The powerful LEDs have an extremely long lifetime yet extremely low power consumption. There is no need for lamp change, and there are no downtimes for servicing. **Help the environment while saving money and increasing productivity at the same time.**

Patented for continuous operation

The motorized objective nosepiece is encapsulated and, like the entire system, designed for the most demanding cleanroom requirements. This is a solution that keeps the microscope in service for years, however tough the conditions.

Effective protection of the samples

The focus stop works both mechanically and electronically to protect samples from inadvertent damage. With the large vertical adjustment range of the focus and individually extendable working distance, **every sample height is accommodated**, from microelectronic components to polished metal sections, composites or minerals.

System integration means single-source supply

With the Leica DM8000 M/DM12000 M, you have a complete system: the microscope, camera and the Leica Application Suite (LAS) software are perfectly matched.

Or upgrade the Leica DM8000 M/DM12000 M to an inspection or review system by choosing a wafer loader, matching accessories such as vacuum wafer chucks, and by installing inspection software or film thickness measurement software.



The objective nosepiece of the Leica DM8000 M/DM12000 M is designed to meet the most demanding cleanroom specifications, also



Upgrade to an inspection or review system with wafer loader and customized inspection software

Easy to use, even in the cleanroom

Designed to the highest ergonomic standards, the controls are specifically intended for the more difficult conditions in the cleanroom.



Ergonomics in perfection – for consistent, reliable results
The tube and focus knobs can be optimally adjusted to specific body size to reduce user fatigue.

Perfect Ergonomics and Convenience



Ergonomics means higher quality

It has been proven that ergonomically-designed workplaces help increase productivity and enhance work quality. Adaptable to any user with its individually adjustable Ergotube and height-adjustable focus knobs, the Leica DM8000 M/DM12000 M is ideal for routine inspection and other applications.

All controls are easy to reach, so that users don't have to take their eyes and hands away from the microscope to switch to a different contrast technique or illumination. The camera's shutter release key is integrated with the microscope stand, also. **Convenient for the user and saves time.**

Helps prevent user error

Even for users with no microscope skills, the Leica DM8000 M/DM12000 M is easy to use. The controls are preassigned using the memory function, **reducing the risk of operation errors**.

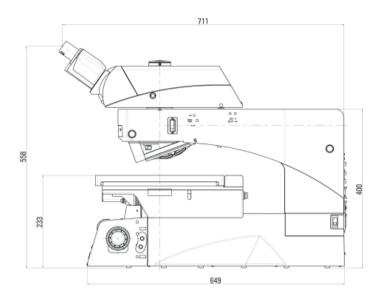
Intelligent support

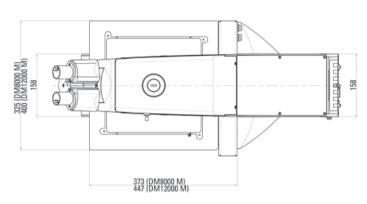
The contrast can be selected at the press of a button with the integrated contrast manager – the relevant parameters are adjusted accordingly. The integrated illumination manager automatically adapts the illumination to the chosen objective. Ultra-easy operation helps avoid errors and saves time.

For the inspection of strongly reflecting surfaces such as blank wafers, the focus finder is an intelligent feature for quickly focusing on the detail of interest.

Inspection tasks can be clearly and simply defined by different user authorizations where several users with different skill levels work at the same microscope.

Technical Data





Systems	Leica DM8000 M	Leica DM12000 M	
Optical system	Leica HC optics (optical system corrected to infinity)		
Viewing tube	Trinocular Ergotube with upright and unreversed image Switching positions (eyepiece/camera): 100/0 and 0/100 100/0 and 50/50		
Macro imaging	Super widefield overview image with up to 40 mm scan field on the sample		
Illumination system	- Full LED incident light illumination; viewing techniques: Brightfield, darkfield, DIC, qualitative POL, oblique illumination, UV, OUV - Full LED transmitted light illumination; viewing techniques: Brightfield, qualitative POL		
Status feedback	Status indicator on front Service interval indicator (on back of instrument)		
Operation support	Integrated contrast manager Integrated illumination manager		
Objective nosepiece	Motorized, brightfield/darkfield objectives (M32), 6-position		
Microscope stages	Manual inspection stage 8 x 8"; 202 x 202 mm travel range, integrated rapid adjustment; for incident and transmitted light techniques	Manual inspection stage 12 x 12"; 302 x 302 mm travel range, integrated rapid adjustment; for incident and transmitted light techniques	
	Scanning stage 8 x 8"; 202 x 202 mm travel range, motorized, 4 mm pitch; for incident and transmitted light techniques	Scanning stage 12 x 12"; 302 x 302 mm travel range, motorized, 4 mm pitch; for incident and transmitted light techniques	
Control units	Joystick with 4 freely programmable function keys Leica SmartMove, x,y,z control with 4 freely programmable function keys Leica STP6000 SmartTouch, x,y,z control with 4 freely programmable function keys		
Focus	Heavy-duty manual 2-stage focus, coarse and fine mode; 35 mm travel range; height-adjustable focus knobs Precision 3-stage focus with coarse, fine and super fine mode; 35 mm adjustment range; height-adjustable focus knobs Motorized 2-stage focus; 35 mm travel range; high reproducibility; parfocality compensation		
Electrical system	Supply voltage: 100-120/220-240 V AC, 50/60 Hz		
Weight	approx. 41 kg (of which microscope approx. 36,1 kg)	approx. 52 kg (of which microscope approx. 36,5 kg)	
Ambient conditions	For use in industrial environments with EMC (Class A threshold). If used in a protected environment, instruments may influence each other Ambient temperature: 15°C – 35°C Relative humidity: 80% for temperatures up to 33°C (without condensation) Voltage fluctuations: +/- 10% Over-voltage category: Il according to IEC60664 Contamination class: 2 according to IEC60664		



Can be delivered in cleanroom packaging (two-layer packaging) on request.

"With the user, for the user" Leica Microsystems

Leica Microsystems operates globally in four divisions, where we rank with the market leaders.

• Life Science Division

The Leica Microsystems Life Science Division supports the imaging needs of the scientific community with advanced innovation and technical expertise for the visualization, measurement, and analysis of microstructures. Our strong focus on understanding scientific applications puts Leica Microsystems' customers at the leading edge of science.

Industry Division

The Leica Microsystems Industry Division's focus is to support customers' pursuit of the highest quality end result. Leica Microsystems provide the best and most innovative imaging systems to see, measure, and analyze the microstructures in routine and research industrial applications, materials science, quality control, forensic science investigation, and educational applications.

Biosystems Division

The Leica Microsystems Biosystems Division brings histopathology labs and researchers the highest-quality, most comprehensive product range. From patient to pathologist, the range includes the ideal product for each histology step and high-productivity workflow solutions for the entire lab. With complete histology systems featuring innovative automation and Novocastra™ reagents, Leica Microsystems creates better patient care through rapid turnaround, diagnostic confidence, and close customer collaboration.

Medical Division

The Leica Microsystems Medical Division's focus is to partner with and support surgeons and their care of patients with the highest-quality, most innovative surgical microscope technology today and into the future.

The statement by Ernst Leitz in 1907, "with the user, for the user," describes the fruitful collaboration with end users and driving force of innovation at Leica Microsystems. We have developed five brand values to live up to this tradition: Pioneering, High-end Quality, Team Spirit, Dedication to Science, and Continuous Improvement. For us, living up to these values means: Living up to Life.

Active worldwide

Australia:	North Ryde	Tel. +61 2 8870 3500	Fax +61 2 9878 1055
Austria:	Vienna	Tel. +43 1 486 80 50 0	Fax +43 1 486 80 50 30
Belgium:	Groot Bijgaarden	Tel. +32 2 790 98 50	Fax +32 2 790 98 68
Canada:	Richmond Hill/Ontario	Tel. +1 905 762 2000	Fax +1 905 762 8937
Denmark:	Ballerup	Tel. +45 4454 0101	Fax +45 4454 0111
France:	Nanterre Cedex	Tel. +33 811 000 664	Fax +33 1 56 05 23 23
Germany:	Wetzlar	Tel. +49 64 41 29 40 00	Fax +49 64 41 29 41 55
Italy:	Milan	Tel. +39 02 574 861	Fax +39 02 574 03392
Japan:	Tokyo	Tel. +81 3 5421 2800	Fax +81 3 5421 2896
Korea:	Seoul	Tel. +82 2 514 65 43	Fax +82 2 514 65 48
Netherlands:	Rijswijk	Tel. +31 70 4132 100	Fax +31 70 4132 109
People's Rep. of China:	Hong Kong	Tel. +852 2564 6699	Fax +852 2564 4163
Portugal:	Lisbon	Tel. +351 21 388 9112	Fax +351 21 385 4668
Singapore		Tel. +65 6779 7823	Fax +65 6773 0628
Spain:	Barcelona	Tel. +34 93 494 95 30	Fax +34 93 494 95 32
Sweden:	Kista	Tel. +46 8 625 45 45	Fax +46 8 625 45 10
Switzerland:	Heerbrugg	Tel. +41 71 726 34 34	Fax +41 71 726 34 44
United Kingdom:	Milton Keynes	Tel. +44 1908 246 246	Fax +44 1908 609 992
USA:	Bannockburn/Illinois	Tel. +1 847 405 0123	Fax +1 847 405 0164

and representatives in more than 100 countries

